

Solutions for Innovation



Atomic Resolution Analytical Electron Microscope

JEM-ARM200F NEOARM

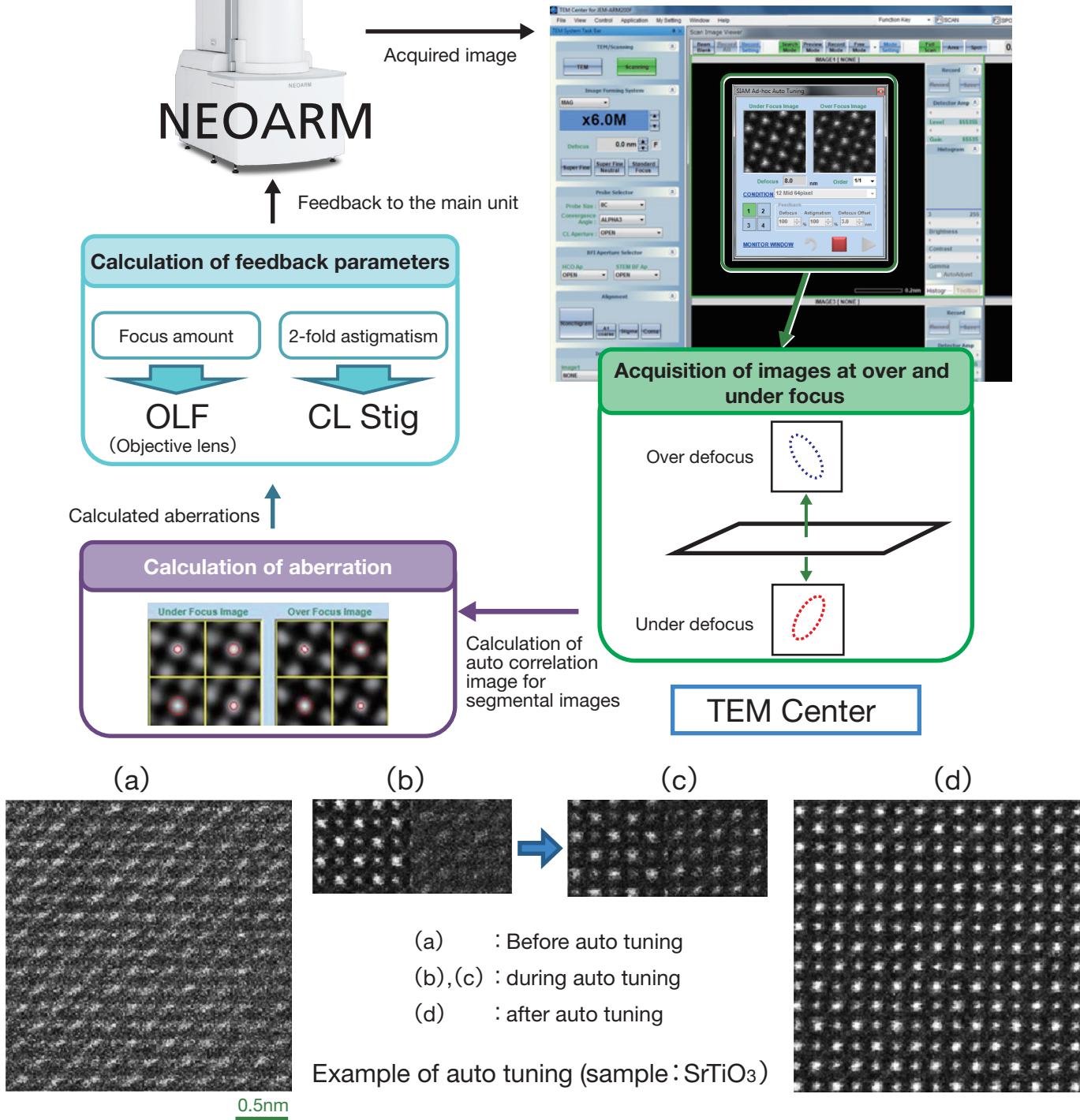
Ad-hoc Auto Tuning

Auto Tuning for HR-STEM for crystalline sample.



Ad-hoc Auto Tuning

Auto Tuning for HR-STEM for crystalline sample.
(focus and 2-fold astigmatism correction)



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